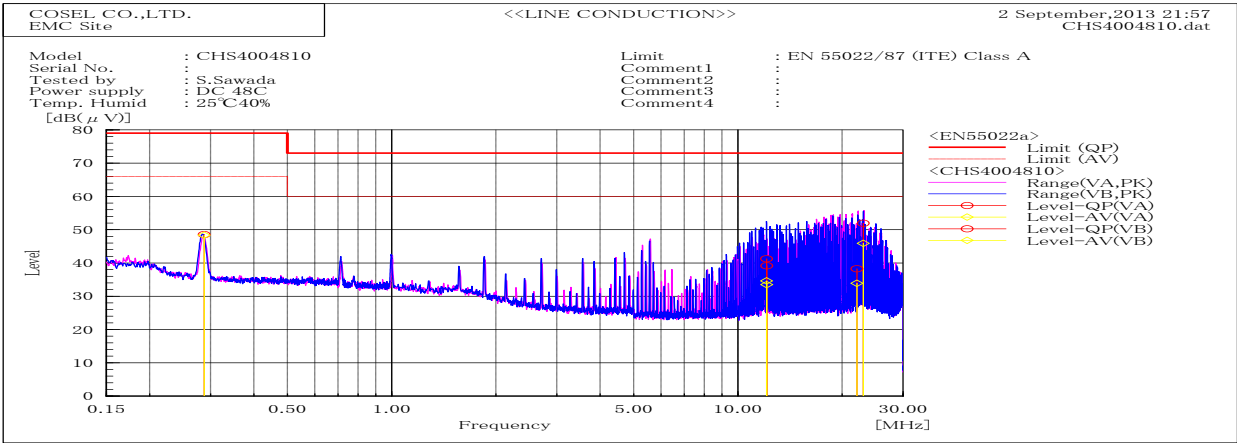
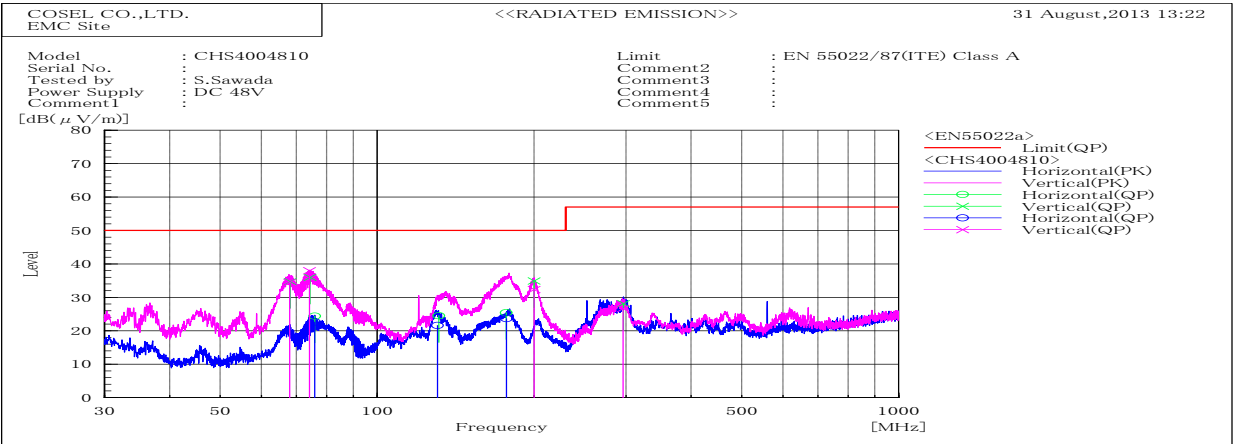


DATA SHEET		Date	03-Sep-13
Model	CHS4004810	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Sawada



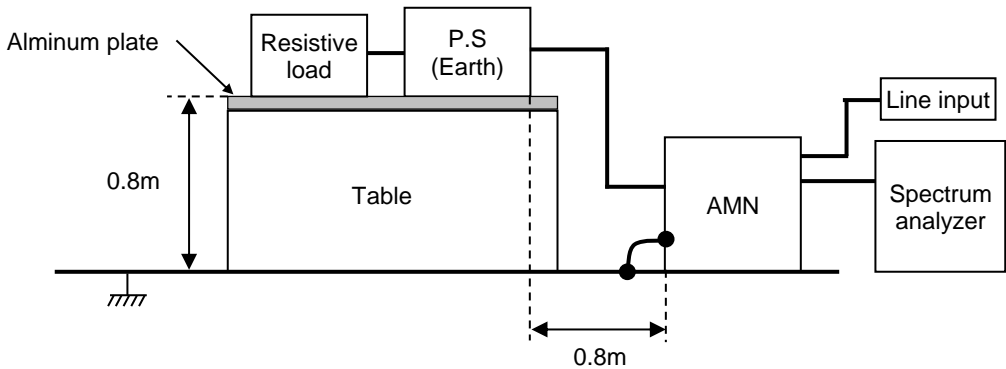
Frequency MHz	Harm	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.28741		VB	28.4	28.2	20.1	48.5	48.3	79	66	30.5	17.7	Pass	
12.1016		VB	20.6	14	20.6	41.2	34.6	73	60	31.8	25.4	Pass	
12.12645		VA	18.4	12.8	20.7	39.1	33.5	73	60	33.9	26.5	Pass	
22.07725		VB	17.3	13	20.9	38.2	33.9	73	60	34.8	26.1	Pass	
23.0421		VA	30.9	24.9	21	51.9	45.9	73	60	21.1	14.1	Pass	



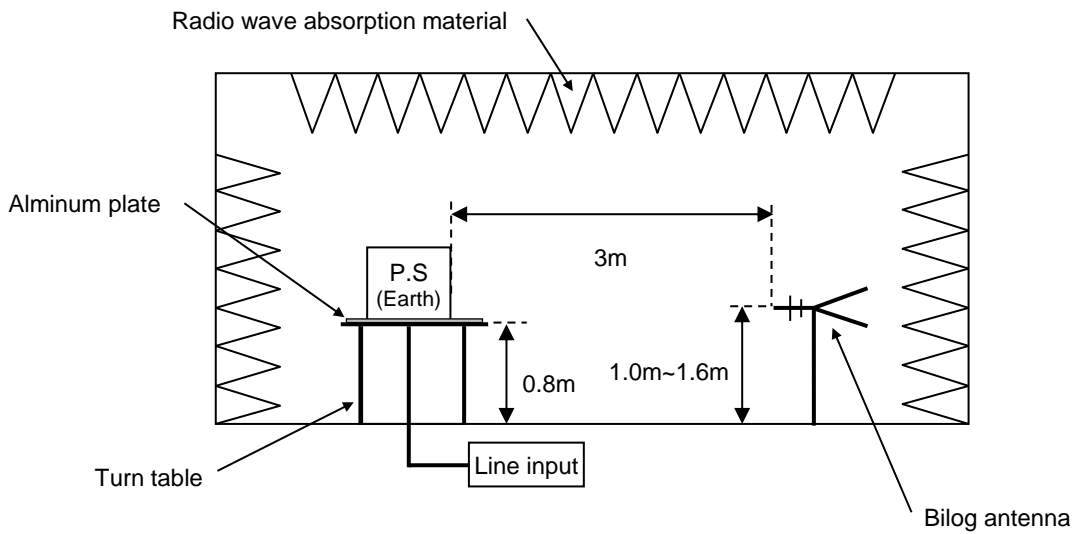
Frequency MHz	Polarization	Stability	Reading dB(μV)		Space Loss dB	Level dB(mW)		Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV		QP	AV						
67.939	V	Stable	55.7	-21		34.7		50	15.3	Pass	116	55	
74.181	V	Stable	56.4	-20.4		36		50	14	Pass	121	63	
75.899	H	Stable	47.5	-23.1		24.4		50	25.6	Pass	144	186	
130.472	H	Stable	44.3	-19.8		24.5		50	25.5	Pass	112	187	
177	H	Stable	47.8	-22.4		25.4		50	24.6	Pass	155	161	
199.863	V	Stable	50.5	-15.6		34.9		50	15.1	Pass	103	3	
296.124	V	Stable	43.8	-15.7		28.1		57	28.9	Pass	139	200	

DATA SHEET		Date	03-Sep-13
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Sawada

1. Line conduction



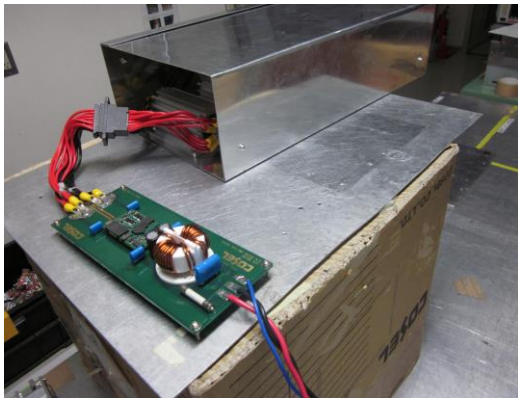
2. Radiated emission



Test: EMI
Model Name:CHS40048□

○ Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○ Testing circuitry

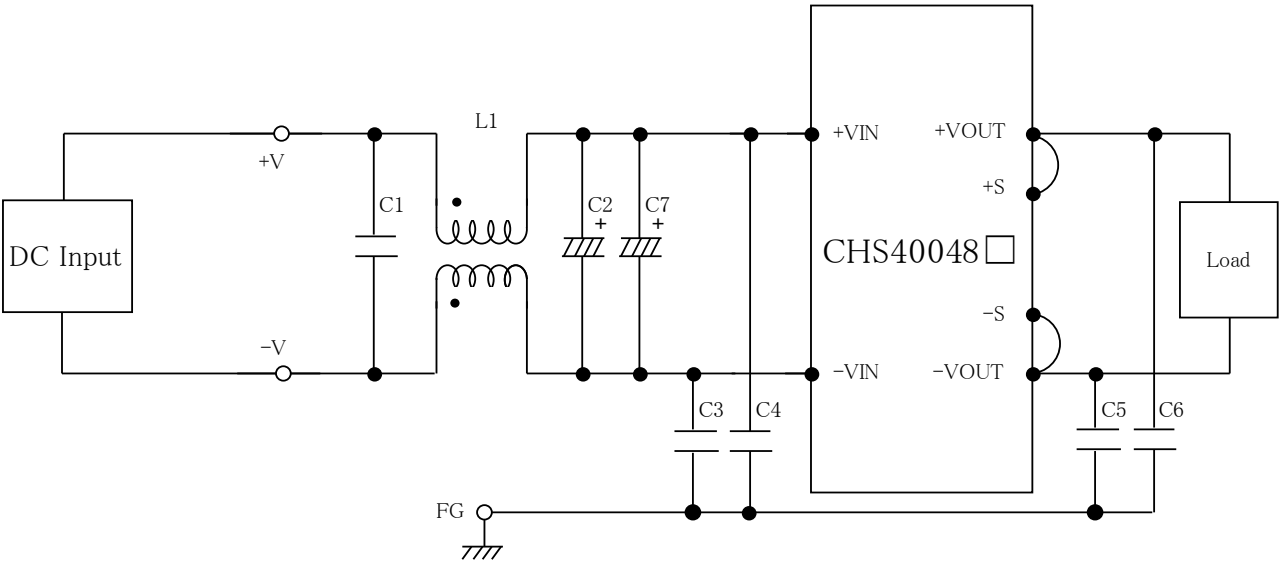


Fig.1 Testing circuitry

- L1 : 1mH SC-20-10JH (TOKIN)
- C1 : 250V 2.2 μ F FPD22E225J4 (NITSUKO)
- C2,C7 : 100V 100 μ F PWseries (nichicon)
- C3,C4 : 630V 0.068 μ F FPD22J683J4 (NITSUKO)
- C5,C6 : 630V 0.033 μ F FPD22J333J4 (NITSUKO)